WHAT IS CLAIMED IS:

1. A method comprising:

accessing design data including an electronic image of an integrated circuit to be tested;

determining whether a pin of the integrated circuit has been assigned to a port in a multi-port automated test environment;

enabling a displayable pin indicator based at least in part upon the determination of whether a pin is assigned to a port; and

displaying the electronic image and the displayable pin indicator.

- 2. A method according to claim 1 wherein the displayable pin indicator is indicative of a pin not assigned to a port.
- 3. A method according to claim 1 wherein the displayable pin indicator is indicative of a pin assigned to a plurality of ports.
- 4. A method according to claim 1 wherein the displayable pin indicator is indicative of a pin which is assigned to a port.
- 5. A method according to claim 1 which further includes iterating the determining, enabling and displaying steps on a pin by pin basis for a group of one or more pins.
- 6. A method according to claim 1 in which the determining, enabling and displaying steps are performed for a group of pins.
- 7. A method according to claim 1 wherein the steps of enabling and displaying a displayable pin indicator comprises highlighting selected from the group consisting of: filling-in, shading, coloring, grayscaling, brightlining, cross-hatching, blinking, shimmering, animating, adding text, encircling, boxing and highlighting associated text, and enabling popup indicators.
- 8. A method according to claim 1 which further comprises selecting a pin to be assigned after the display of the electronic image and the displayable pin indicator.

- 9. A method according to claim 1 which further comprises assigning a pin to a port after the display of the electronic image and the displayable pin indicator.
- 10. A method according to claim 9 which further includes accessing a pin assignment capability for the step of assigning the pin to a port after the display of the electronic image and the displayable pin indicator.
- 11. A method according to claim 1 in which the step of determining whether a pin is assigned to a port includes determining whether the pin is not assigned.
- 12. A method according to claim 1 in which the step of determining whether a pin is assigned to a port includes determining whether the pin is multiply assigned.
- 13. A method according to claim 1 in which the step of determining whether a pin is assigned to a port includes determining whether an entire group of one or more pins is assigned to the port.
- 14. A method according to claim 1 which further includes:

selecting a mode of operation, wherein the mode of operation is indicative of which type of displayable in indicator may be enabled and displayed during the enabling and displaying steps;

performing at least one combination of the determining, enabling and displaying steps on a pin by pin basis for a group of one or more pins of interest.

- 15. A method according to claim 14 further comprising selecting a further discrete mode of operation after said step of performing at least one combination of the determining, enabling and displaying steps.
- 16. A method according to claim 15 in which each of the members of the group consisting of the mode of operation and the further discrete mode of operation are selected from the group consisting of: determining whether the pin is not assigned; determining whether the pin is multiply assigned; and determining whether an entire group of one or more pins is assigned to a port.

17. A method for developing at least a portion of an integrated circuit test in a multi-port automated test environment comprising:

accessing design data including an electronic image of an integrated circuit to be tested;

determining whether a pin of the integrated circuit is assigned to a port in a multi-port automated test environment;

indicating with a displayable indicator the result of the determining step; and assigning a pin to a port as a result of the determining and indicating steps.

- 18. A method according to claim 17 wherein the step of determining whether a pin of the integrated circuit is assigned to a port includes determining whether the pin is assigned as desired; and wherein the step of assigning a pin to a port further includes assigning such pin if such pin is not assigned as desired.
- 19. A method according to claim 17 which further includes displaying the design data including the electronic image of the integrated circuit to be tested.
- 20. A method according to claim 19 further comprising: using a displayable indicator to highlight on the electronic image one or more pins which are not assigned as desired.
- 21. A method according to claim 17 which further includes accessing test program data including pin to port assignment data.
- 22. A method according to claim 21 which further includes:

evaluating the test program data in comparison to the design data to determine which pins are not assigned as desired;

displaying the design data including the electronic image of the integrated circuit to be tested; and

highlighting on the electronic image pins which are not assigned as desired.

23. A system for developing at least a portion of an integrated circuit test in a multi-port automated test environment, the system comprising:

an automated test controller which is adapted to communicate test information to automated test equipment, said controller also being adapted to provide for:

accessing design data including an electronic image of an integrated circuit to be tested;

determining whether a pin of the integrated circuit is assigned to a port as desired; and

assigning such pin to a port if not assigned as desired.

24. Apparatus comprising:

a computer readable medium; wherein a computer program is stored on the computer readable medium, the computer readable medium being adapted for developing at least a portion of an integrated circuit test in a multi-port automated test environment; said computer program comprising:

program code to access design data including an electronic image of an integrated circuit to be tested;

program code to determine whether a pin of the integrated circuit is assigned to a port; and

program code to assign such pin to a port if not assigned as desired.